



Paper No. 7

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OFFICE OF PETITIONS

In re Application of  
Govindan Nair  
Application No. 09/752,095  
Filed: December 30, 2000  
Attorney Docket No. 42390P9928

ON PETITION

This is a decision on the petition under 37 CFR 1.137(b), filed July 21, 2003, to revive the above-identified application.

The above-identified application became abandoned for failure to reply in a timely manner to the Notice to File Missing Parts of Application (Notice) mailed February 14, 2001. The Notice set a period for reply of two (2) months from the mail date of the Notice. No extensions of time under the provisions of 37 CFR 1.136(a) were obtained. Accordingly, the above-identified application became abandoned after midnight April 14, 2001.

In response to the Notice to File Missing Parts, petitioner submitted with the instant petition \$1300 for the petition to revive fee, \$710 for the basic filing fee, an executed declaration and \$130 for the late filing of the oath/declaration, \$18 for the claims in excess of twenty, and three (3) sheets of drawings containing figures 1-3.

Petitioner submitted \$710 for the basic filing fee. However, effective January 1, 2003, the basic filing fee was increased to \$750. Therefore, per authorization given in the Fee Transmittal filed with the instant petition, the balance of \$40 has been charged to petitioner's deposit account.

Since all the requirements for a grantable petition have been met, the petition is **GRANTED**.

The power of attorney combined with the oath/declaration filed July 21, 2003, has been made of record.

The application is being forwarded to the Office of Initial Patent Examination for further processing, using the declaration filed on July 21, 2003.

Telephone inquiries concerning this decision should be directed to Andrea Smith at (703) 308-6711.

Andrea Smith  
Petitions Examiner  
Office of Petitions  
Office of the Deputy Commissioner  
for Patent Examination Policy